



# FDP8N60ZU / FDPF8N60ZUT N-Channel MOSFET, FRFET 600V, 6.5A, 1.35 $\Omega$

#### **Features**

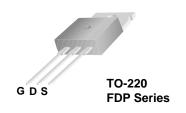
- $R_{DS(on)} = 1.15 m\Omega$  ( Typ.) @  $V_{GS} = 10 V$ ,  $I_D = 3.25 A$
- Low gate charge (Typ. 20nC)
- Low C<sub>rss</sub> ( Typ. 10pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



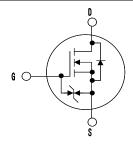
# **Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.







# **MOSFET Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted\*

Symbol		Parameter		FDP8N60ZU	FDPF8N60ZUT	Units	
V <sub>DSS</sub>	Drain to Source Voltage	Drain to Source Voltage		6	V		
$V_{GSS}$	Gate to Source Voltage	Gate to Source Voltage		±30		V	
	Drain Current	-Continuous (T <sub>C</sub> = 25°C)		6.5	6.5*	^	
ID	Drain Current	-Continuous (T <sub>C</sub> = 100°C)		3.9	3.9*	Α	
I <sub>DM</sub>	Drain Current	Prain Current - Pulsed (Note 1)		26	26*	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy		(Note 2)	420		mJ	
I <sub>AR</sub>	Avalanche Current		(Note 1)	6.5		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	13.5		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20		V/ns	
D	Dower Discipation	$(T_C = 25^{\circ}C)$		135	34.5	W	
$P_{D}$	Power Dissipation  - Derate above 25°C			1.05	0.28	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to	+150	°С		
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	00	°C	

\*Drain current limited by maximum junction temperature

# **Thermal Characteristics**

Symbol	Parameter	FDP8N60ZU	FDPF8N60ZUT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.95	3.6	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP8N60ZU	FDP8N60ZU	TO-220	-	-	50
FDPF8N60ZUT	FDPF8N60ZUT	TO-220F	-	-	50

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250\mu A, V_{GS} = 0V, T_J = 25^{\circ} C$	600	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.7	-	V/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 600V, V_{GS} = 0V$	-	-	25	
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480V, T_{C} = 125^{\circ}C$	-	-	250	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 30V, V_{DS} = 0V$	-	-	±10	μΑ

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 3.25A$	•	1.15	1.35	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40V, I_{D} = 3.25A$	-	7	-	S

# **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 25V V 0V	-	950	1265	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25V, V_{GS} = 0V$ f = 1MHz		110	150	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 = 1101112	-	10	15	pF
$Q_g$	Total Gate Charge at 10V		-	20	26	nC
$Q_{gs}$	Gate to Source Gate Charge	$V_{DS} = 480V, I_{D} = 6.5A$	-	5	-	nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	$V_{GS} = 10V$ (Note 4)	1	8	-	nC

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time			-	20	50	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 300V, I_D = 6.5A$		-	30	70	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 25\Omega$ , $V_{GS} = 10V$		-	55	120	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4)	-	35	80	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-	-	6.5	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	26	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 6.5A$	-	-	1.6	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 6.5A	-	40	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	-	42	-	nC

- **Notes:**1. Repetitive Rating: Pulse width limited by maximum junction temperature 2: L = 20mH,  $I_{AS}$  = 6.5A,  $V_{DD}$  = 50V,  $R_{C}$  = 25 $\Omega$ , Starting  $T_{J}$  = 25°C 3:  $I_{SD}$  ≤ 6.5A, di/dt ≤ 200A/ $\mu$ s,  $V_{DD}$  ≤ BV $_{DSS}$ , Starting  $T_{J}$  = 25°C 4: Essentially Independent of Operating Temperature Typical Characteristics

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

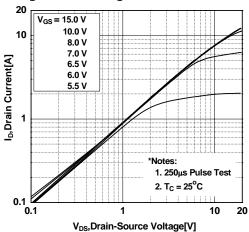


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

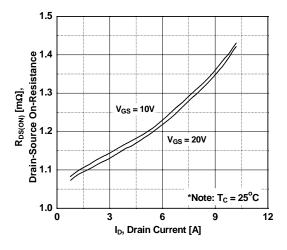


Figure 5. Capacitance Characteristics

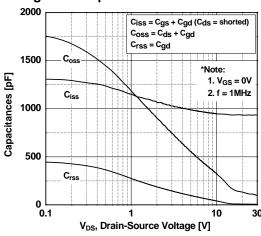


Figure 2. Transfer Characteristics

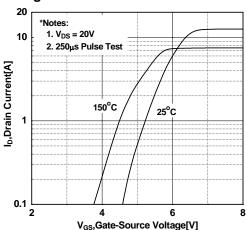


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

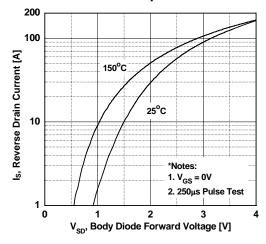
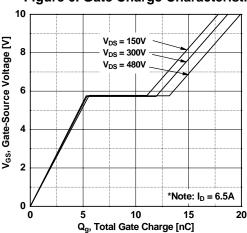


Figure 6. Gate Charge Characteristics



# **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

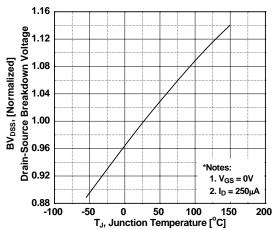


Figure 8. Maximum Safe Operating Area - FDPF8N60ZUT

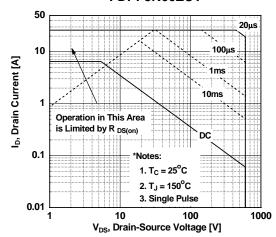


Figure 9. Maximum Drain Current vs. Case Temperature

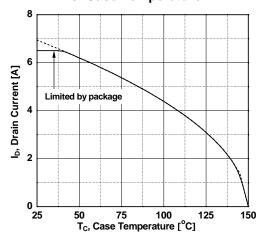
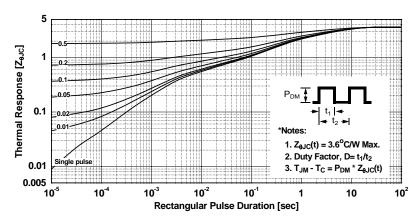
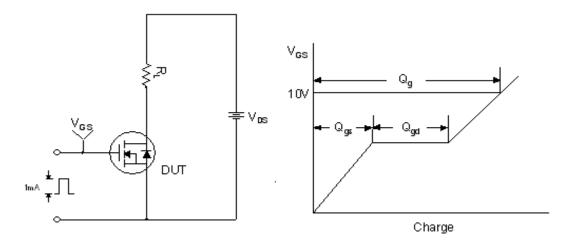


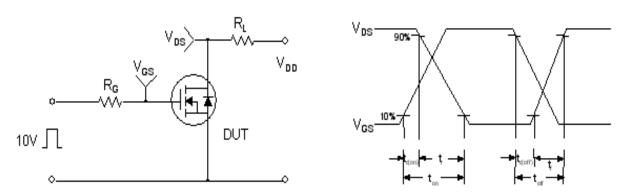
Figure 10. Transient Thermal Response Curve - FDPF8N60ZUT



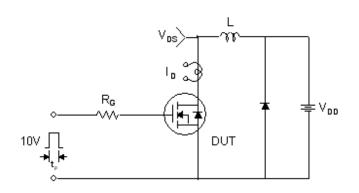
# **Gate Charge Test Circuit & Waveform**

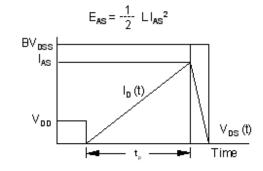


## **Resistive Switching Test Circuit & Waveforms**

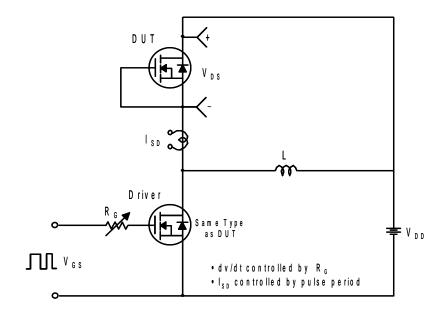


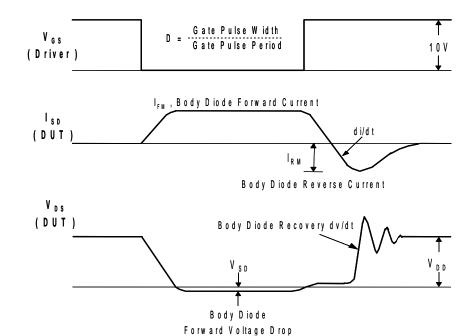
**Unclamped Inductive Switching Test Circuit & Waveforms** 





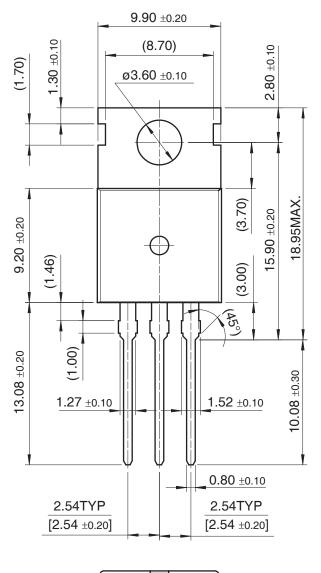
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

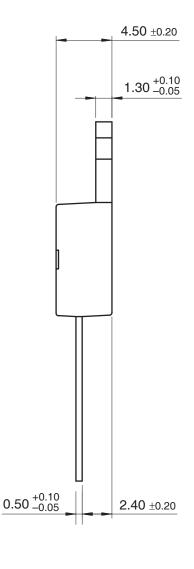




# **Mechanical Dimensions**

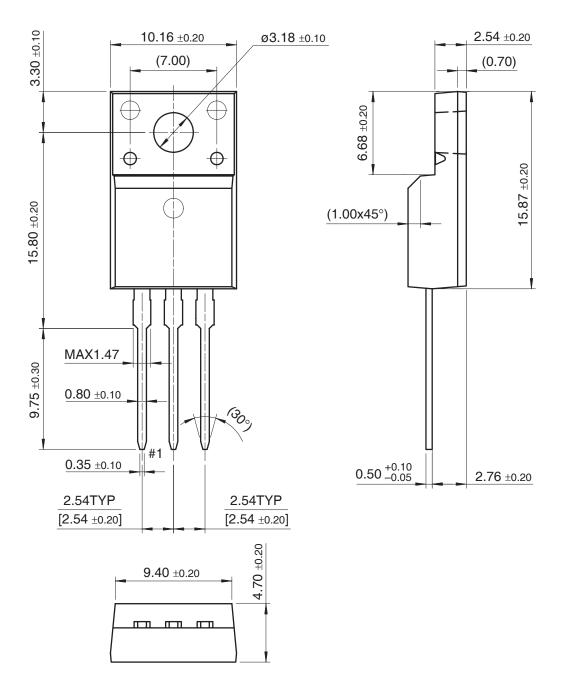
# TO-220





# **Mechanical Dimensions**

# TO-220F



Dimensions in Millimeters





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